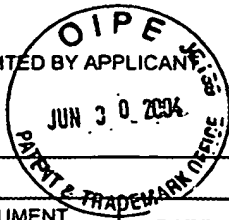


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## LIST OF REFERENCES CITED BY APPLICANT

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## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO					
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

<i>SM</i>	AW	B. A. GALWAS, et al., IEEE Transactions on Instrumentation and Measurement, vol. 46, no. 2, XP-000725675, pages 511-514, "DIELECTRIC MEASUREMENTS USING A COAXIAL RESONATOR OPENED TO A WAVEGUIDE BELOW CUT-OFF", April 1, 1997
<i>SM</i>	AX	S. O. NELSON, et al., IEEE Transactions on Instrumentation and Measurement, vol. 47, no. 5, XP-000862430, pages 1201-1204, "SENSING PULVERIZED MATERIAL MIXTURE PROPORTIONS BY RESONANT CAVITY MEASUREMENTS", October 1998
	AY	
	AZ	<i>None</i>

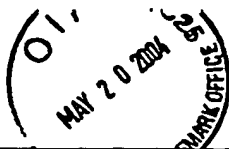
☐ Additional References sheet(s) attached

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## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO	6-138076	05/20/1994	JAPAN		X
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

JM	AW	Y. IJIMA, pages 20-23, "ELECTRONIC MONTHLY", 1998				
JM	AX	JIS R 1627, Japanese Standards Association, pages 1-18, "TESTING METHOD FOR DIELECTRIC PROPERTIES OF FINE CERAMICS AT MICROWAVE FREQUENCY", July 1996				
JM	AY	JIS R 1641, Japanese Standards Association, pages 1-29, "TESTING METHOD FOR DIELECTRIC PROPERTIES OF FINE CERAMIC PLATES AT MICROWAVE FREQUENCY", January 2002				
	AZ					<input type="checkbox"/> Additional References sheet(s) attached

Examiner

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